PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor: Buxton, et al. Docket No.: TAI.0800

Serial No.: 10/730,388 Examiner: Khuu, Cindy D.

Filing Date: December 07, 2003 Art Unit: 2863

Title: Methods and Apparatus for Data

Analysis

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner of Patents P.O. Box 1450 Alexandria, Virginia 22313-1450

Commissioner:

In accordance with the duty of disclosure under 37 C.F.R. §1.56 and pursuant to 37 C.F.R. §\$1.97-1.98, the reference or references listed and identified on the attached PTO/SB/08-based form are being submitted for consideration by the Examiner.

The applicant further provides the following information for which no written references are possessed:

- The article: Variance Reduction Using Wafer Patterns, Daasch, McNames, Bockelman, Cota (2003);
- The company LSI may have a commercial SPP solution using Nearest-Neighbor Residual (NNR) technology that may be relevant; and
- Mr. Charles Meyerson of Medtronic may have information about LSI's NNR/SPP techniques that may be relevant.

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The preceding information and the attached references are cited only in the interest of candor and without any admission that they constitute statutory prior art or contain matter which

anticipates the invention or which would render the same obvious, either singly or in

combination, to a person of ordinary skill in the art.

This Information Disclosure Statement (IDS) is being filed under 37 C.F.R. §1.97(c)

before the mailing date of any final action under 37 C.F.R. §1.113, a notice of allowance under

37 C.F.R. §1.311, or an action that otherwise closes prosecution of the application. The IDS is

accompanied by the fee set forth in 37 C.F.R. §1.17(p). If there are any questions concerning

this IDS, the Examiner is requested to contact the undersigned.

Respectfully submitted,

Date: 22 DEC 06

Daniel J. Noblitt Reg. No. 35,969

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Substitu	te for form 1449/PTO			Application Number	10/730,388	
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				Art Unit	2863	
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Examiner Initials*	Cite No.1	Include name of the author (In CAPITAL LETTERS), title of the aride (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
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				Art Unit	2863		
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Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, sorial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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		NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*						
	MIGUELANEZ, EMILIO, DIWA: Device Independent Wafermap Analysis, 2003					
		MIGUELANEZ, EMILIO, DIWA: Device Independent Wafermap Analysis, 2003 (PRESENTATION)				
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STATEMENT BY APPLICANT	First Named Inventor	Buxton	
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Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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		US- 6,787,379	09-07-2004	Madge et al.						
		^{US-} 6,807,655	10-19-2004	Rehani et al.	J					
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